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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Toshikazu KITAJIMA et al. Date : February 1, 2005
 Serial No. : 10/624,871 Group Art Unit : 2863
 Filed : July 21, 2003 Examiner : Xiuquin Sun
 Confirmation No. : 7650
 For : FILM THICKNESS MEASURING METHOD, RELATIVE
 DIELECTRIC CONSTANT MEASURING METHOD, FILM
 THICKNESS MEASURING APPARATUS, AND RELATIVE
 DIELECTRIC CONSTANT MEASURING APPARATUS

via FACSIMILE - (703) 872-9306

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL

Sir:

This is a response to the Office Action mailed November 3, 2004 in the above-identified application. Reconsideration of the application is respectfully requested.

FEE CALCULATION

Any additional fee required has been calculated as follows:

If checked, "Small Entity" status is claimed.

NO. CLAIMS AFTER AMENDMENT	HIGHEST NO. PREVIOUSLY PAID FOR	EXTRA PRESENT	RATE	ADDIT. FEE
TOTAL 11	MINUS 20	* = -0-	X (\$25 SE or \$50)	\$ -0-
INDEP. 3	MINUS 4	** = -0-	X (\$100 SE or \$200)	\$ -0-
FIRST PRESENTATION OF MULTIPLE DEPENDENT CLAIM			X (\$180 SE or \$360)	\$ -0-

* not less than 20 ** not less than 3

TOTAL \$ -0-

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